

Data Sheet

Description

The ACNV2601 is an optically coupled gate that combines an AlGaAs light-emitting diode and an integrated photo detector housed in a widebody package. The distance-through-insulation (DTI) between the emitting diode and photo-detector is at 2 mm. The output of the detector IC is an open collector Schottky clamped transistor. The internal shield provides a guaranteed common mode transient immunity specification of 20 kV/μs at $V_{cm} = 1500V$.

With creepage and clearance of greater than 13 mm, ACNV2601 is designed to provide high isolation voltage (7500 V_{rms}). It can withstand a continuous high working voltage of 2262 V_{peak} and a surge voltage of 12,000 V_{peak}, meeting IEC60747-5-5, UL, and CSA standard for reinforced insulation. ACNV2601 provides the high insulation voltage protection at a high data rate of 10 MBd.

CAUTION

It is advised that normal static precautions be taken in handling and assembly of this component to prevent damage and/or degradation which may be induced by ESD. The components featured in this data sheet are not to be used in military or aerospace applications or environments

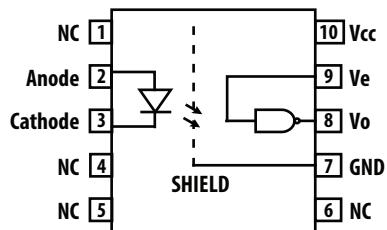
Features

- High voltage insulation with minimum 13-mm creepage and clearance
- 20 kV/μs minimum common mode rejection (CMR) at $V_{CM} = 1500V$
- High speed: 10 MBd typical
- TTL compatible
- Open collector output
- Guaranteed AC and DC performance over wide temperature: -40°C to +105°C
- Available in 10-pin widebody packages
- Safety approval:
 - Approval at 7500 V_{rms} for 1 minute per UL1577
 - CSA
 - IEC/EN/DIN EN 60747-5-5 with $V_{iorm} = 2262 V_{peak}$

Applications

- High voltage insulation
- Instrument input/output isolation
- Line receivers
- Ground loop elimination
- Isolation of high-speed logic systems
- Microprocessor system interfaces

Functional Diagram



Truth Table (Positive Logic)

| LED | ENABLE | OUTPUT |
|-----|--------|--------|
| On | H | L |
| Off | H | H |
| On | L | H |
| Off | L | H |
| On | NC | L |
| Off | NC | H |

NOTE A 0.1- μ F bypass capacitor must be connected between pins V_{CC} and GND.

Ordering Information

ACNV2601 is UL recognized with 7500 V_{rms} for 1 minute per UL1577.

| Part Number | Option | Package | Surface Mount | Gull Wing | Tape & Reel | UL 7500 V _{rms} /1 Minute Rating | IEC/EN/DIN EN 60747-5-5 | Quantity |
|-------------|----------------|----------------|---------------|-----------|-------------|---|-------------------------|--------------|
| | RoHS Compliant | | | | | | | |
| ACNV2601 | -000E | 500 mil DIP-10 | | | | X | X | 35 per tube |
| | -300E | | X | X | | X | X | 35 per tube |
| | -500E | | X | X | X | X | X | 500 per reel |

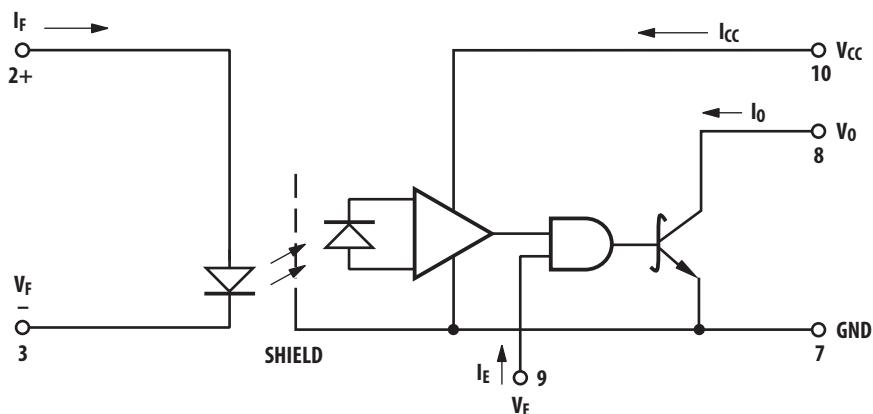
To order, choose a part number from the Part Number column and combine with the desired option from the Option column to form an order entry.

Example 1:

ACNV2601-500E to order product of 500 mil DIP-10 Widebody with Gull Wing Surface Mount package in Tape and Reel packaging with both UL 7500 V_{rms}/1 min and IEC/EN/DIN EN 60747-5-5 Safety Approval in RoHS compliant.

Option data sheets are available. Contact your Broadcom sales representative or authorized distributor for information.

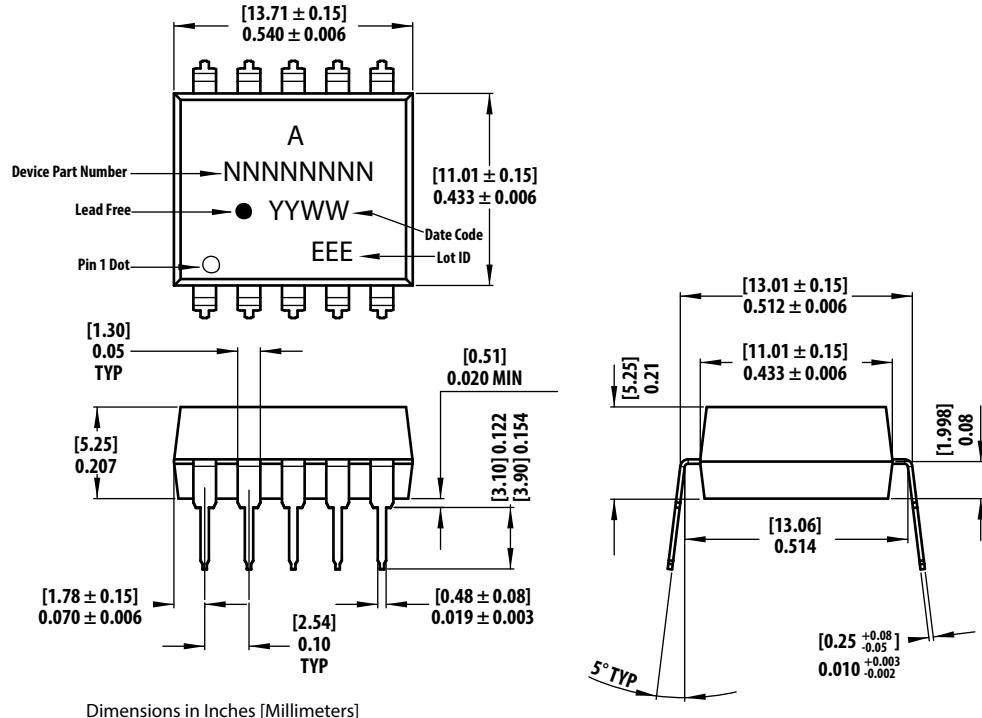
Schematic



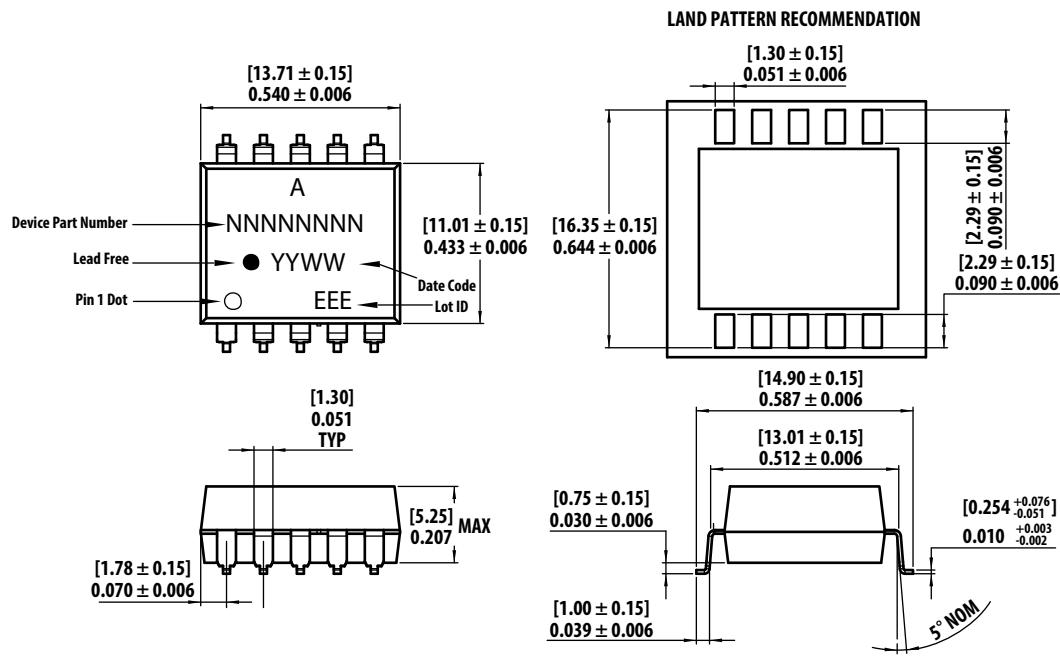
NOTE Use of a 0.1- μ F bypass capacitor connected between pins of 7 and 10 is recommended.

Package Drawings

10-Pin Widebody (500 mils) DIP Package



10-Pin Widebody (500 mils) DIP Package with Gull Wing Surface Mount Option 300



Solder Reflow Profile

Recommended reflow condition as per JEDEC Standard, J-STD-020 (latest revision). Non-Halide Flux should be used.

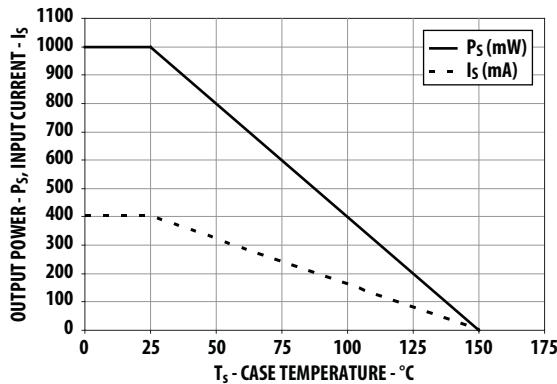
Insulation and Safety Related Specifications

| Parameter | Symbol | ACNV2601 | Unit | Conditions |
|---|--------|----------|------|--|
| Minimum External Air Gap (External Clearance) | L(101) | 13 | mm | Measured from input terminals to output terminals, shortest distance through air. |
| Minimum External Tracking (External Creepage) | L(102) | 13 | mm | Measured from input terminals to output terminals, shortest distance path along body. |
| Minimum Internal Plastic Gap (Internal Clearance) | | 2.0 | mm | Through insulation distance conductor to conductor, usually the straight line distance thickness between the emitter and detector. |
| Minimum Internal Tracking (Internal Creepage) | | 4.6 | mm | Measured from input terminals to output terminals, along internal cavity. |
| Tracking Resistance (Comparative Tracking Index) | CTI | 200 | V | DIN IEC 112/VDE 0303 Part 1. |
| Isolation Group | | IIIa | | Material Group (DIN VDE 0110, 1/89, Table 1). |

IEC/EN/DIN EN 60747-5-5 Insulation Characteristics^a

| Description | Symbol | Characteristic | Unit |
|--|--|-------------------|-------------------|
| Installation Classification per DIN VDE 0110/1.89, Table 1 For Rated Mains Voltage $\leq 600 \text{ V}_{\text{rms}}$ For Rated Mains Voltage $\leq 1000 \text{ V}_{\text{rms}}$ | | I – IV I – III | |
| Climatic Classification | | 55/105/21 | |
| Pollution Degree (DIN VDE 0110/1.89) | | 2 | |
| Maximum Working Insulation Voltage | V_{IORM} | 2262 | V_{peak} |
| Input to Output Test Voltage, Method b ^a $V_{\text{IORM}} \times 1.875 = V_{\text{PR}}$, 100% Production Test with $t_m = 1 \text{ sec}$, Partial Discharge $< 5 \text{ pC}$ | V_{PR} | 4241 | V_{peak} |
| Input to Output Test Voltage, Method a ^a $V_{\text{IORM}} \times 1.6 = V_{\text{PR}}$, Type and Sample Test, $t_m = 10 \text{ sec}$, Partial Discharge $< 5 \text{ pC}$ | V_{PR} | 3619 | V_{peak} |
| Highest Allowable Overvoltage (Transient Overvoltage $t_{\text{ini}} = 60 \text{ sec}$) | V_{IOTM} | 12000 | V_{peak} |
| Safety-Limiting Values — Maximum Values Allowed in the Event of a Failure Case Temperature Input Current ^b Output Power ^b | T_S $I_S, \text{ INPUT}$ $P_S, \text{ OUTPUT}$ | 150 400 1 | °C mA W |
| Insulation Resistance at T_S , $V_{\text{IO}} = 500\text{V}$ | R_S | $>10^9$ | Ω |

- a. Refer to the optocoupler section of the Isolation and Control Components Designer's Catalog, under Product Safety Regulations section, (IEC/EN/DIN EN 60747-5-5) for a detailed description of Method a and Method b partial discharge test profiles.
- b. Refer to the following figure for dependence of P_S and I_S on ambient temperature:



NOTE These optocouplers are suitable for safe electrical isolation only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.

Absolute Maximum Ratings

| Parameter | Symbol | Min. | Max. | Unit |
|---|-------------------|------|---------------------------------------|------|
| Storage Temperature | T_S | -55 | 125 | °C |
| Operating Temperature | T_A | -40 | 105 | °C |
| Average Input Current | $I_F(\text{AVG})$ | — | 20 | mA |
| Reverse Input Voltage | V_R | — | 3 | V |
| Input Power Dissipation | P_I | — | 40 | mW |
| Supply Voltage (1 Minute Maximum) | V_{CC} | — | 7 | V |
| Enable Input Voltage (Not to exceed V_{CC} by more than 500 mV) | V_E | — | $V_{CC} + 0.5$ | V |
| Enable Input Current | I_E | — | 5 | mA |
| Output Collector Current | I_O | — | 50 | mA |
| Output Collector Voltage | V_O | — | 7 | V |
| Output Collector Power Dissipation | P_O | — | 85 | mW |
| Lead Solder Temperature | T_{LS} | — | 245°C for 10 sec, up to seat plane | |

Recommended Operating Conditions

| Parameter | Symbol | Min. | Max. | Unit | Notes |
|---|------------|------|----------|-----------|-------|
| Input Current, Low Level | I_{FL}^a | 0 | 250 | μA | |
| Input Current, High Level | I_{FH}^b | 9 | 16 | mA | c |
| Power Supply Voltage | V_{CC} | 4.5 | 5.5 | V | |
| Low Level Enable Voltage | V_{EL} | 0 | 0.8 | V | |
| High Level Enable Voltage | V_{EH} | 2.0 | V_{CC} | V | |
| Operating Temperature | T_A | -40 | 105 | °C | |
| Fan Out (at $R_L = 1 \text{ k}\Omega$) | N | — | 5 | TTL Loads | |
| Output Pull-up Resistor | R_L | 330 | 4k | Ω | |

- a. The off condition can also be guaranteed by ensuring that $V_{FL} \geq 0.8V$.
- b. The initial switching threshold is 8 mA or less. It is recommended that 9 mA to 16 mA be used for best performance and to permit at least a 20% LED degradation guardband.
- c. Peaking circuits may produce transient input currents up to 50-mA, 50-ns maximum pulse width, provided average current does not exceed 20 mA.

Electrical Specifications (DC)

Over recommended operating conditions unless otherwise specified. All typicals at $V_{CC} = 5V$, $T_A = 25^\circ C$.

| Parameter | Symbol | Min. | Typ. | Max. | Unit | Test Conditions | | Fig. | Notes |
|-------------------------------------|---------------------------|------|------|------|---------------|---|-----------------------------------|---------------|-------|
| High Level Output Current | I_{OH} | — | 5.5 | 100 | μA | $V_{CC} = 5.5V, V_E = 2.0V$ $V_O = 5.5V, I_{FL} = 250 \mu A$ | | | a |
| Input Threshold Current | I_{TH} | — | 3.5 | 8 | mA | $V_{CC} = 5.5V, V_E = 2.0V,$ $V_O = 0.6V, I_{OL} > 13 mA$ | | 1, 2 | a |
| Low Level Output Voltage | V_{OL} | — | 0.35 | 0.6 | V | $V_{CC} = 5.5V, V_E = 2.0V,$ $I_F = 8 mA, I_{OL(Sinking)} = 13 mA$ | | 1, 2, 3, 4 | a |
| High Level Supply Current | I_{CCH} | — | 7.0 | 12 | mA | $V_E = 0.5V$ | $V_{CC} = 5.5 V,$ $I_F = 0 mA$ | | |
| | | — | 6.5 | — | | $V_E = V_{CC}$ | | | |
| Low Level Supply Current | I_{CCL} | — | 9.0 | 13 | mA | $V_E = 0.5V$ | $V_{CC} = 5.5V,$ $I_F = 10 mA$ | | |
| | | — | 8.5 | — | | $V_E = V_{CC}$ | | | |
| High Level Enable Current | I_{EH} | — | -0.7 | — | mA | $V_{CC} = 5.5V, V_E = 2.0V$ | | | |
| Low Level Enable Current | I_{EL} | — | -0.9 | — | mA | $V_{CC} = 5.5V, V_E = 0.5V$ | | | |
| High Level Enable Voltage | V_{EH} | 2.0 | — | — | mA | $V_{CC} = 5.5 V, V_E = 2.0V$ | | | a |
| Low Level Enable Voltage | V_{EL} | — | — | 0.8 | mA | $V_{CC} = 5.5V, V_E = 0.5V$ | | | |
| Input Forward Voltage | V_F | 1.25 | 1.64 | 1.85 | V | $T_A = 25^\circ C$ | $I_F = 10 mA$ | 5 | |
| | | 1.2 | — | 2.05 | | | | | |
| Input Reverse Breakdown Voltage | BV_R | 5 | — | — | V | $I_R = 100 \mu A, T_A = 25^\circ C$ | | | |
| Input Capacitance | C_{IN} | — | 60 | — | pF | $f = 1 MHz, V_F = 0V$ | | | |
| Input Diode Temperature Coefficient | $\Delta V_F / \Delta T_A$ | — | -1.9 | — | $mV/^\circ C$ | $I_F = 10 mA$ | | | |

a. No external pull-up is required for a high logic state on the enable input. If the V_E pin is not used, tying V_E to V_{CC} results in improved CM_R performance

Switching Specifications (AC)

Over recommended temperature ($T_A = -40^\circ\text{C}$ to $+105^\circ\text{C}$), $V_{CC} = 5\text{V}$, $I_F = 10\text{ mA}$ unless otherwise specified. All typicals are at $T_A = 25^\circ\text{C}$, $V_{CC} = 5\text{V}$.

| Parameter | Symbol | Min. | Typ. | Max. | Unit | Test Conditions | | Fig. | Notes | |
|--|-----------------------|------|------|------|-------|---|---|------------|---------|--|
| Propagation Delay Time to High Output Level | t_{PLH} | 30 | 50 | 80 | ns | $T_A = 25^\circ\text{C}$ | $R_L = 350\Omega$, $C_L = 15\text{ pF}$ | 6, 7, 8 | a, b | |
| | | | | 120 | | | | | c, b | |
| Propagation Delay Time to Low Output Level | t_{PHL} | 35 | 55 | 80 | ns | $T_A = 25^\circ\text{C}$ | $R_L = 350\Omega$, $C_L = 15\text{ pF}$ | 6, 7, 8, 9 | b | |
| | | | | 120 | | | | | | |
| Pulse Width Distortion | $ t_{PHL} - t_{PLH} $ | — | 5 | 40 | ns | $R_L = 350\Omega$, $C_L = 15\text{ pF}$ | | 10 | b | |
| Propagation Delay Skew | t_{PSK} | — | — | 50 | ns | | | | d, b | |
| Output Rise Time (10% to 90%) | T_r | — | 25 | — | ns | | | 10 | b | |
| Output Fall Time (10% to 90%) | T_f | — | 10 | — | ns | | | | b | |
| Propagation Delay Time of Enable from V_{EH} to V_{EL} | t_{ELH} | — | 30 | — | ns | $R_L = 350\Omega$, $C_L = 15\text{ pF}$, $V_{EL} = 0\text{V}$, $V_{EH} = 3\text{V}$ | | 11, 12 | e | |
| Propagation Delay Time of Enable from V_{EL} to V_{EH} | t_{EHL} | — | 20 | — | ns | $R_L = 350\Omega$, $C_L = 15\text{ pF}$, $V_{EL} = 0\text{V}$, $V_{EH} = 3\text{V}$ | | 11, 12 | f | |
| Output High Level Common Mode Transient Immunity | $ CM_H $ | 20 | 25 | — | kV/μs | $V_{CC} = 5\text{V}$, $I_F = 0\text{ mA}$, $V_{O(MIN)} = 2\text{V}$, $R_L = 350\Omega$, $T_A = 25^\circ\text{C}$, $V_{CM} = 1500\text{V}$ | | 13 | g, h, b | |
| Output Low Level Common Mode Transient Immunity | $ CM_L $ | 20 | 25 | — | kV/μs | $V_{CC} = 5\text{V}$, $I_F = 10\text{ mA}$, $V_{O(MAX)} = 0.8\text{V}$, $R_L = 350\Omega$, $T_A = 25^\circ\text{C}$, $V_{CM} = 1500\text{V}$ | | | h, i, b | |

- The t_{PLH} propagation delay is measured from the 5 mA point on the falling edge of the input pulse to the 1.5V point on the rising edge of the output pulse.
- No external pull-up is required for a high logic state on the enable input. If the V_E pin is not used, tying V_E to V_{CC} results in improved CM_R performance.
- The t_{PHL} propagation delay is measured from the 5 mA point on the rising edge of the input pulse to the 1.5V point on the falling edge of the output pulse.
- t_{PSK} is equal to the worst-case difference in t_{PHL} and/or t_{PLH} that is seen between units at any given temperature and specified test conditions.
- The t_{ELH} enable propagation delay is measured from the 1.5V point on the falling edge of the enable input pulse to the 1.5V point on the rising edge of the output pulse.
- The t_{EHL} enable propagation delay is measured from the 1.5V point on the rising edge of the enable input pulse to the 1.5V point on the falling edge of the output pulse.
- CM_H is the maximum tolerable rate of rise of the common mode voltage to ensure that the output remains in a high logic state (i.e., $V_O > 2.0\text{V}$).
- For sinusoidal voltages, $(|dV_{CM}|/dt)_{max} = \pi f_{CM} V_{CM(p-p)}$.
- CM_L is the maximum tolerable rate of fall of the common mode voltage to ensure that the output remains in a low logic state (i.e., $V_O < 0.8\text{V}$).

Package Characteristics

All typicals are at $T_A = 25^\circ\text{C}$.

| Parameter | Symbol | Min. | Typ. | Max. | Unit | Test Conditions | | Fig. | Notes |
|--------------------------|-----------|-----------|------|------|-----------|--|--|------|-------|
| Input-Output Insulation | V_{ISO} | 7500 | — | — | V_{rms} | $RH < 50\%$ for 1 min., $T_A = 25^\circ\text{C}$ | | | a, b |
| Input-Output Resistance | R_{I-O} | 10^{12} | — | — | Ω | $V_{I-O} = 500\text{V}$ | | | a |
| Input-Output Capacitance | C_{I-O} | — | 0.5 | 0.6 | pF | $f = 1\text{ MHz}$, $T_A = 25^\circ\text{C}$ | | | a |

- Device considered a two-terminal device: pins 1, 2, 3, 4 and 5 shorted together, and pins 6, 7, 8, 9 and 10 shorted together.
- In accordance with UL1577, each optocoupler is proof tested by applying an insulation test voltage $\geq 9000\text{ V}_{rms}$ for one second (leakage detection current limit, $I_{L-O} \leq 5\text{ μA}$). This test is performed before the 100% production test for partial discharge (Method b) shown in the [IEC/EN/DIN EN 60747-5-5 Insulation Characteristics^a](#) table, if applicable.

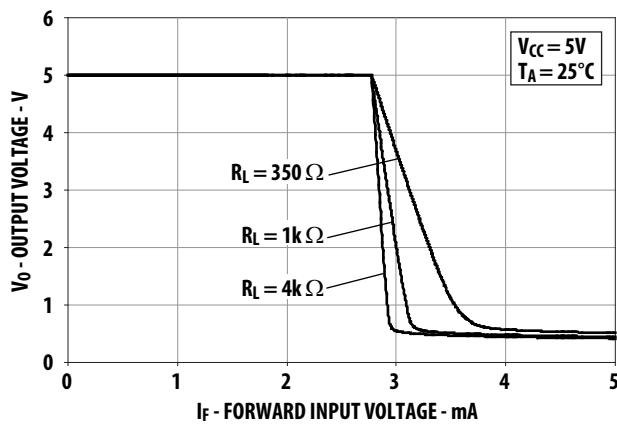
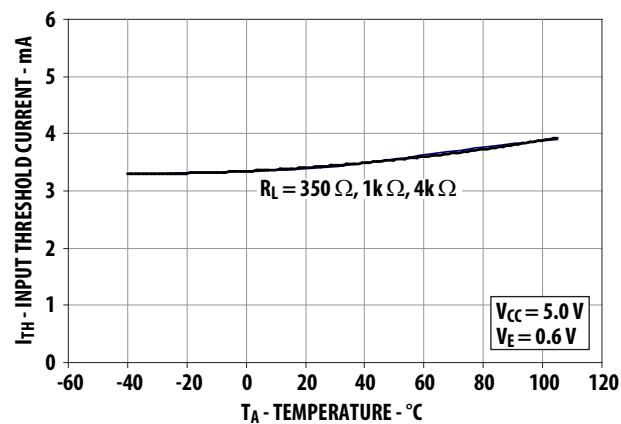
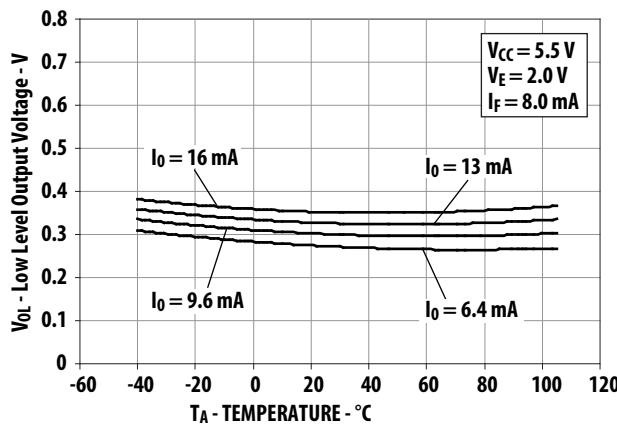
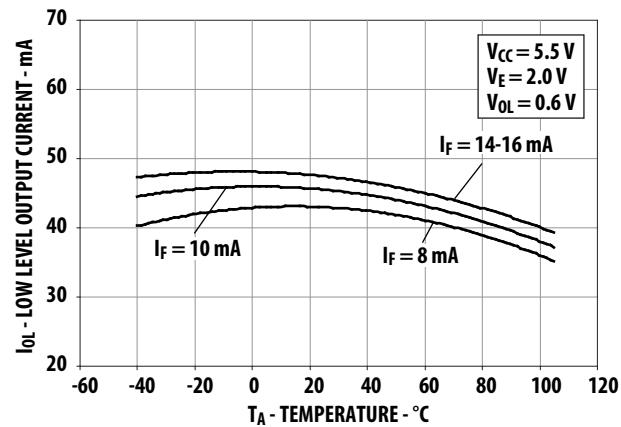
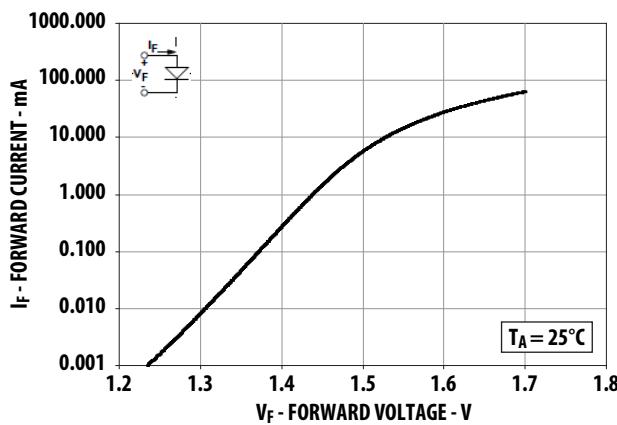
Figure 1 Typical Output Voltage vs. Forward Input Voltage Current**Figure 2 Typical Input Threshold Current vs. Temperature****Figure 3 Typical Low Level Output Voltage vs. Temperature****Figure 4 Typical Low Level Output Current vs. Temperature****Figure 5 Typical Input Diode Forward Characteristic**

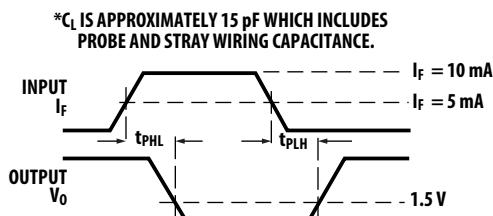
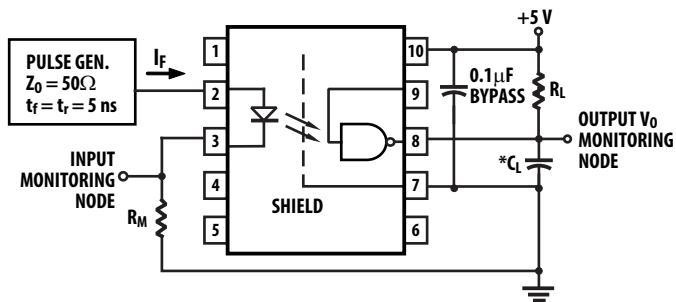
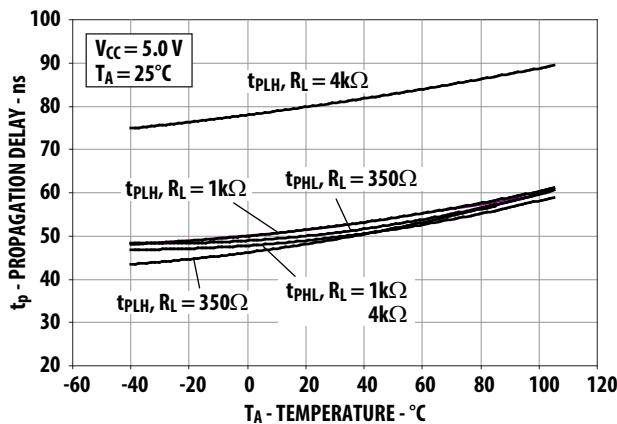
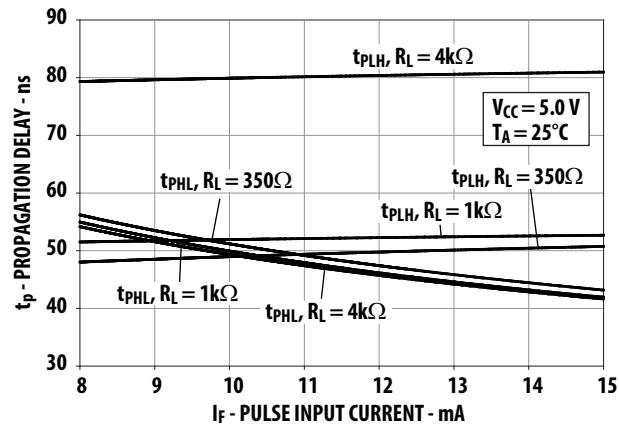
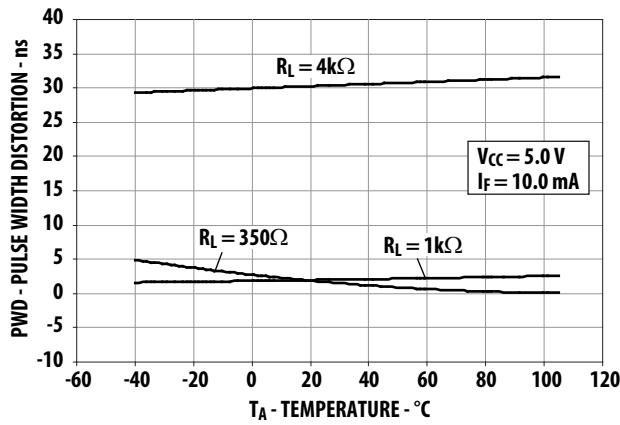
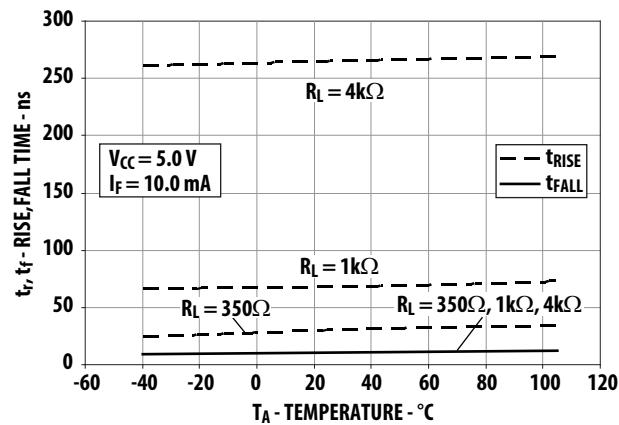
Figure 6 Test Circuit for t_{PHL} and t_{PLH} **Figure 7 Typical Propagation Delay vs. Temperature****Figure 8 Typical Propagation Delay vs. Pulse Input Current****Figure 9 Typical Pulse Width Distortion vs. Temperature****Figure 10 Typical Rise and Fall Time vs. Temperature**

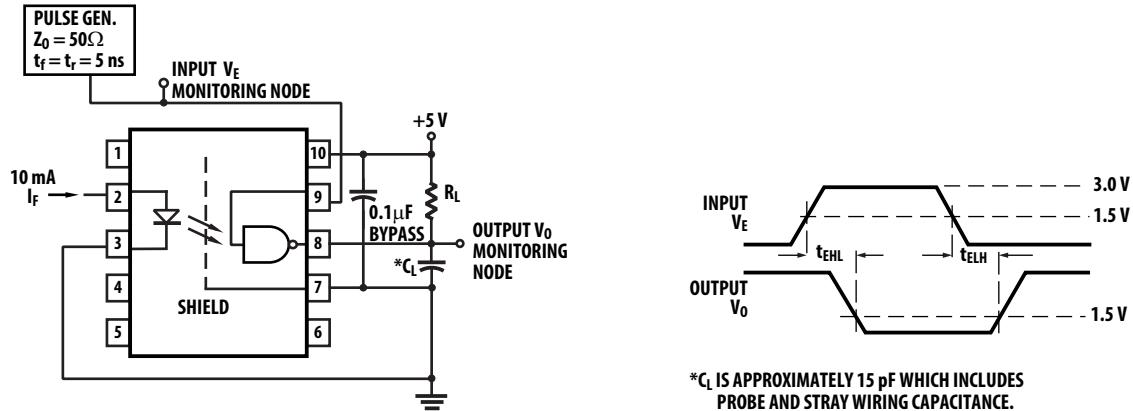
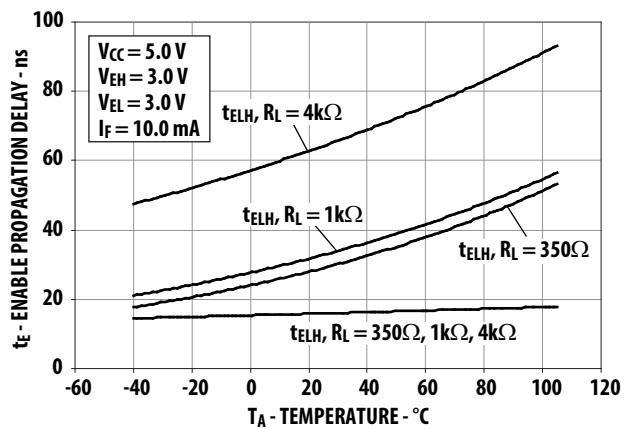
Figure 11 Test Circuit for t_{EHL} and t_{ELH} **Figure 12** Typical Enable Propagation Delay vs. Temperature

Figure 13 Test Circuit for Common Mode Transient Immunity and Typical Waveforms

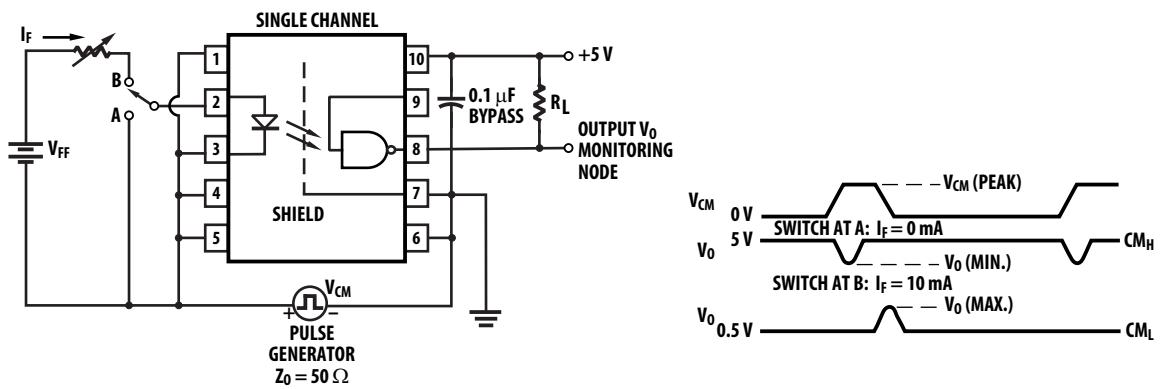
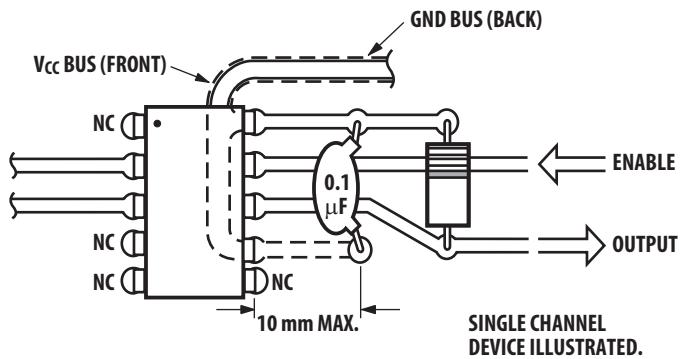


Figure 14 Recommended Printed Circuit Board Layout



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